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| Form PTO 1449 (Modified) | | U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE | | ATTY DOCKET NO. 249715US2SDIV | | SERIAL NO. New DIV Application | |
| LIST OF REFERENCES CITED BY APPLICANT | | | | APPLICANT Hideo ANDO, et al. | | | |
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| | AX | | | | | | <input type="checkbox"/> Additional References sheet(s) attached |
| Examiner <i>Huey Nguyen</i> | | | | | Date Considered <i>11/11/04</i> | | |
| *Examiner: Initial if reference is considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant. | | | | | | | |

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| <i>HW</i> | AY | Explanation of Circumstances concerning Accelerated Examination for Japanese Patent Application No. 1999-256240 (w/English translation) | | | | | |
| | AZ | | | | | <input type="checkbox"/> Additional References sheet(s) attached | |
| Examiner <i>Henry Nguyen</i> | | | | | Date Considered <i>11/11/04</i> | | |
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